

# **HZU-L Series**

# Silicon Epitaxial Planar Zener Diode for Low Noise Application

REJ03G0043-0200Z Rev.2.00 Aug.18.2003

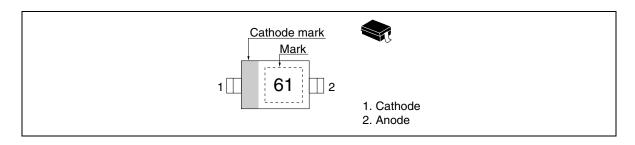
#### **Features**

- Diode noise level of this series is approximately 1/3-1/10 lower than the HZ series.
- Low leakage and low zener impedance.
- Wide spectrum from 5.2V through 38V of zener voltage provide flexible application.
- Ultra small Resin Package (URP) is suitable for surface mount design.

### **Ordering Information**

Type No.	Mark	Package Code		
HZU-L Series	Type No.	URP		

#### Pin Arrangement



# **Absolute Maximum Ratings**

 $(Ta = 25^{\circ}C)$ 

Item	Symbol	Value	Unit	
Power dissipation	Pd	150	mW	
Junction temperature	Tj	150	°C	
Storage temperature	Tstg	-55 to +150	°C	

#### **Electrical Characteristics**

 $(Ta = 25^{\circ}C)$ 

		Zener Voltage		Reverse Curren		e Current	Dynamic	Resistance	<b>ESD-Capability</b>
		V <sub>z</sub> (V)	<sub>*</sub> 1	Test Condition	Ι <sub>R</sub> (μ <b>Α</b> )	Test Condition	r <sub>d</sub> (Ω)	Test Condition	(V)* <sup>2</sup>
Type	Grade	Min	Max	I <sub>z</sub> (mA)	Max	V <sub>R</sub> (V)	Max	I <sub>z</sub> (mA)	Min
HZU6L	A1	5.2	5.5	0.5	1	2.0	150	0.5	200
	A2	5.3	5.6	=					
	A3	5.4	5.7	=					
	B1	5.5	5.8	=			80	0.5	_
	B2	5.6	5.9	=					
	B3	5.7	6.0	=					
	C1	5.8	6.1	=			60	0.5	_
	C2	6.0	6.3	=					
	C3	6.1	6.4	=					
HZU7L	A1	6.3	6.6	0.5	1	3.5	60	0.5	200
	A2	6.4	6.7	_					
	A3	6.6	6.9	_					
	B1	6.7	7.0	_					
	B2	6.9	7.2	=					
	B3	7.0	7.3	=					
	C1	7.2	7.6	=					
	C2	7.3	7.7	_					
	C3	7.5	7.9	_					

Notes: 1. Tested with DC.

2. C = 200 pF, R = 0  $\Omega$ , Both forward and reverse direction 1 pulse. Failure criterion ; According to IR spec.

		Zener Voltage		Reverse Current		Dynamic Resistance		ESD-Capability	
		V <sub>z</sub> (V)	<sub>*</sub> 1	Test Condition	I <sub>R</sub> (μΑ)	Test Condition	r <sub>d</sub> (Ω)	Test Condition	(V)* <sup>2</sup>
Туре	Grade	Min	Max	I <sub>z</sub> (mA)	Max	V <sub>R</sub> (V)	Max	I <sub>z</sub> (mA)	Min
HZU9L	A1	7.7	8.1	0.5	1	6.0	60	0.5	200
	A2	7.9	8.3	_					
	A3	8.1	8.5	_					
	B1	8.3	8.7	_					
	B2	8.5	8.9	_					
	B3	8.7	9.1	_					
	C1	8.9	9.3	_					
	C2	9.1	9.5	_					
	C3	9.3	9.7	_					
HZU11L	A1	9.5	9.9	0.5	1	8.0	80	0.5	200
	A2	9.7	10.1	_					
	A3	9.9	10.3	_					
	B1	10.2	10.6	_					
	B2	10.4	10.8	_					
	B3	10.7	11.1	_					
	C1	10.9	11.3	_					
	C2	11.1	11.6	_					
	C3	11.4	11.9	_					
HZU12L	A1	11.6	12.1	0.5	1	10.5	80	0.5	200
	A2	11.9	12.4	_					
	A3	12.2	12.7	_					
	B1	12.4	12.9	_					
	B2	12.6	13.1	_					
	B3	12.9	13.4	_					
	C1	13.2	13.7	_					
	C2	13.5	14.0	_					
	СЗ	13.8	14.3	_					
HZU15L	-1	14.1	14.7	0.5	1	13.0	80	0.5	200
	<del>-</del> 2	14.5	15.1						
	-3	14.9	15.5	_					
HZU16L	-1	15.3	15.9	0.5	1	14.0	80	0.5	200
	<del>-</del> 2	15.7	16.5						
	<del>-3</del>	16.3	17.1	_					

Notes: 1. Tested with DC.

<sup>2.</sup> C = 200 pF, R = 0  $\Omega$ , Both forward and reverse direction 1 pulse. Failure criterion ; According to IR spec.

		Zener Voltage			Reverse Current		<b>Dynamic Resistance</b>		ESD-Capability
		V <sub>z</sub> (V)	*1	Test Condition	Ι <sub>R</sub> (μΑ)	Test Condition	n r <sub>d</sub> (Ω)	Test Condition	(V)* <sup>2</sup>
Type	Grade	Min	Max	I <sub>z</sub> (mA)	Max	V <sub>R</sub> (V)	Max	I <sub>z</sub> (mA)	Min
HZU18L	-1	16.9	17.7	0.5	1	15.0	80	0.5	200
	<del>-2</del>	17.5	18.3	_					
	<del>-3</del>	18.1	19.0	_					
HZU20L	-1	18.8	19.7	0.5	1	18.0	100	0.5	200
	<del>-2</del>	19.5	20.4	_					
	-3	20.2	21.1	_					
HZU22L	-1	20.9	21.9	0.5	1	20.0	100	0.5	200
	<del>-2</del>	21.6	22.6	_					
	-3	22.3	23.3	_					
HZU24L	-1	22.9	24.0	0.5	1	22.0	120	0.5	200
	<del>-2</del>	23.6	24.7	_					
	<del>-3</del>	24.3	25.5	_					
HZU27L	-1	25.2	26.6	0.5	1	24.0	150	0.5	200
	<del>-2</del>	26.2	27.6	_					
	<del>-3</del>	27.2	28.6	_					
HZU30L	-1	28.2	29.6	0.5	1	27.0	200	0.5	200
	<del>-2</del>	29.2	30.6	_					
	<del>-3</del>	30.2	31.6	_					
HZU33L	-1	31.2	32.6	0.5	1	30.0	250	0.5	200
	<del>-2</del>	32.2	33.6	_					
	<del>-</del> 3	33.2	34.6	_					
HZU36L	-1	34.2	35.7	0.5	1	33.0	300	0.5	200
	<del>-2</del>	35.3	36.8	_					
	<del>-3</del>	36.4	38.0	<del>_</del>					

Notes: 1. Tested with DC.

2. C = 200 pF, R = 0  $\Omega$ , Both forward and reverse direction 1 pulse. Failure criterion ; According to IR spec.

#### Mark Code

Туре	Grade	Mark No.	Туре	Grade	Mark No.	Туре	Grade	Mark No.
HZU6L	A1	61	HZU11L	A1	111	HZU20L	-1	201
	A2	62	_	A2	112	_	<del>-2</del>	202
	A3	63	_	A3	113	_	-3	203
	B1	64	_	B1	114	HZU22L	-1	221
	B2	65	_	B2	115	_	<del>-2</del>	222
	B3	66	_	В3	116	_	-3	223
	C1	67	_	C1	117	HZU24L	-1	241
	C2	68	_	C2	118	_	<del>-2</del>	242
	C3	69	_	C3	119	_	-3	243
HZU7L	A1	71	HZU12L	A1	121	HZU27L	-1	271
	A2	72	_	A2	122	_	<del>-2</del>	272
	A3	73	_	A3	123	_	-3	273
	B1	74	<del></del>	B1	124	HZU30L	-1	301
	B2	75	_	B2	125	_	<del>-2</del>	302
	B3	76	<del></del>	B3	126	<del>_</del>	<del>-3</del>	303
	C1	77	<del></del>	C1	127	HZU33L	-1	331
	C2	78	<del></del>	C2	128	<del>_</del>	<del>-2</del>	332
	C3	79	<del></del>	C3	129	<del>_</del>	<del>-3</del>	333
HZU9L	A1	91	HZU15L	-1	151	HZU36L	-1	361
	A2	92	<del></del>	<del>-2</del>	152	<del>_</del>	<del>-2</del>	362
	A3	93	<del></del>	<del>-3</del>	153	_	<del>-3</del>	363
	B1	94	HZU16L	-1	161			
	B2	95	<del></del>	<del>-2</del>	162	<del>_</del>		
	B3	96	<del></del>	<del>-3</del>	163	<del>_</del>		
	C1	97	HZU18L	-1	181	<del>_</del>		
	C2	98	_	<del>-</del> 2	182	_		
	C3	99		<del>-</del> 3	183	<del>-</del>		

Notes: 1. Example of Marking

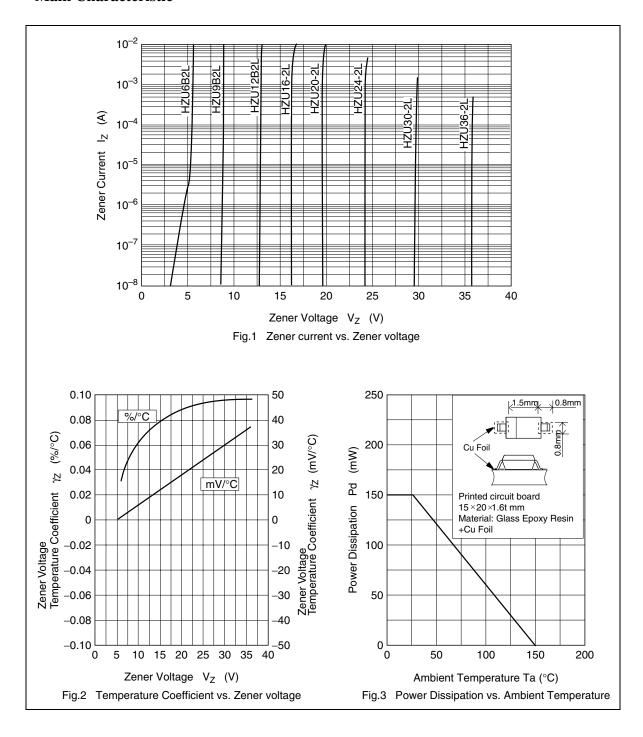
(1) HZU6A1L to HZU9C3L Example of Marking (2) HZU11A1L to HZU36-3L Example of Marking



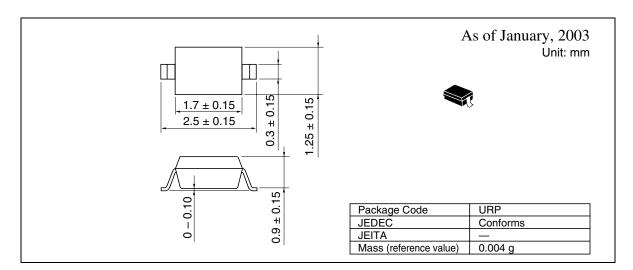


- 2. Type No. is as follows; HZU6A1L, HZU6A2L, ••• HZU12C3L
- 3. Type No. is as follows; HZU15 1L, HZU15 2L, ••• HZU36 3L

#### **Main Characteristic**



# **Package Dimensions**



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